IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application.

- 1. (Cancelled)
- 2. (Currently Amended) A p-type electrode material represented by a composition formula A_XB_YC_Z, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, $0.20 \le X \le 0.35$, $0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$,

A p-type electrode material according to claim 1, characterized in that wherein said A comprises Cu, and said B comprises Fe.

3. (Currently Amended) A p-type electrode material represented by a composition formula A_XB_YC_Z, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, $0.20 \le X \le 0.35$, $0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$,

A-p-type electrode material according to claim 1 or 2, characterized in that wherein said p-

type electrode material has a chalcopyrite structure.

 $0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$.

4. (Currently Amended) A p-type semiconductor element characterized by having a structure wherein a Group II-VI compound semiconductor and [[the]] a p-type electrode material according to claim 1 are in contact with each other.

wherein the p-type electrode material is represented by a composition formula $A_XB_YC_Z$, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, 0.20≤X≤0.35,

5. (Currently Amended) A p-type semiconductor element characterized by comprising:

a semiconductor having a Group II-VI compound semiconductor layer at at least an outermost surface layer, and

[[the]] a p-type electrode material according to claim-1 which is in contact with said semiconductor via said Group II-VI compound semiconductor layer,

wherein the p-type electrode material is represented by a composition formula $A_XB_YC_Z$, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, $0.20 \le X \le 0.35$, $0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$.

6. (Currently Amended) A p-type semiconductor element characterized by comprising:
a semiconductor having a Group II-VI compound semiconductor layer at at least an
outermost surface layer, and

a hole-injection electrode portion placed in contact with said semiconductor via said Group II-VI compound semiconductor layer and made of a solid solution material of a compound $A_XB_YC_Z$ in the form of [[the]] a p-type electrode material according to claim 1 and a Group II-VI compound semiconductor,

wherein the p-type electrode material is represented by a composition formula $A_XB_YC_Z$, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, $0.20 \le X \le 0.35$, $0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$.

- 7. (Previously Presented) A p-type semiconductor element according to claim 6, characterized in that components of said compound $A_XB_YC_Z$ in said hole-injection electrode portion decrease continuously or stepwise from the surface toward said Group II-VI compound semiconductor layer.
 - 8. (Previously Presented) A p-type semiconductor element according to claim 4,

characterized in that the Group II-VI compound semiconductor contains at least Zn as a Group II element and at least one element selected from S and Se as a Group VI element.

9. (Currently Amended) A p-type semiconductor element characterized by having a structure wherein a Group III-V compound semiconductor and [[the]] <u>an</u> electrode material according to claim-1 are in contact with each other,

wherein the electrode material is represented by a composition formula $A_XB_YC_Z$, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, $0.20 \le X \le 0.35$, $0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$.

10. (Currently Amended) A p-type semiconductor element characterized by having a structure wherein an organic semiconductor and [[the]] <u>a</u> p-type electrode material according to elaim 1 are in contact with each other,

wherein the p-type electrode material is represented by a composition formula $A_XB_YC_Z$, characterized in that:

A consists of at least one element selected from Group 1B metal elements,

B consists of at least one element selected from Group 8 metal elements, and

C consists of at least one element selected from S and Se,

wherein mole ratios X, Y, and Z are such that X+Y+Z=1, 0.20≤X≤0.35,

$0.17 \le Y \le 0.30$, and $0.45 \le Z \le 0.55$.

- 11. (Previously Presented) A p-type semiconductor element according to any of claims 4 to 10, characterized in that said p-type semiconductor element is a semiconductor light-emitting element.
- 12. (New) A p-type electrode material according to claim 2, characterized in that said p-type electrode material has a chalcopyrite structure.